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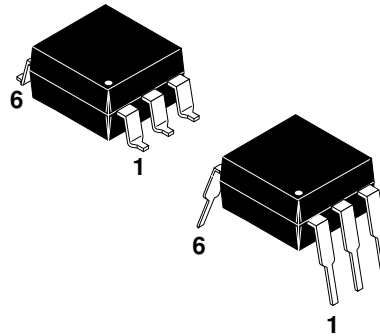
DESCRIPTION

The CNW82, CNW83, CNW84 and CNW85 optocouplers consist of a GaAs infrared emitting diode which is optically coupled to an NPN phototransistor.

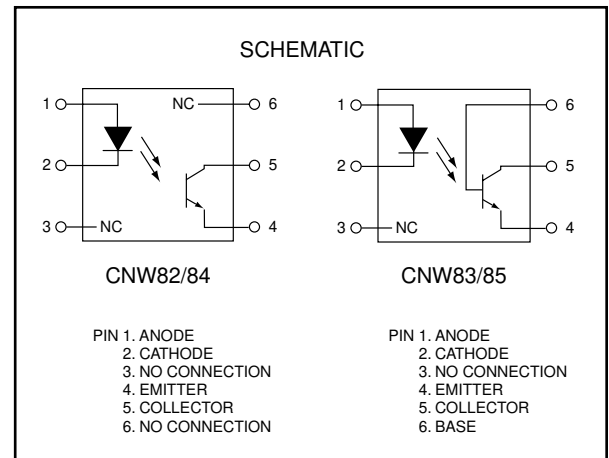
The CNW82 and CNW84 do not have the base pin connected for improved noise immunity.

FEATURES

- Wide body DIL encapsulation, with a pin distance of 10.16 mm.
- Minimum creepage distance 10 mm.
- High current transfer ratio and Low Saturation Voltage, making the device suitable for use with TTL integrated circuits.
- High degree of AC and DC insulation (5900 V (RMS) and 8340 V (DC)).
- Minimum 2 mm isolation thickness between emitter and detector. (CNW84/85 only).
- An external clearance of 9.6 mm minimum and an external creepage distance of 10 mm minimum.
- Collector-Emitter Breakdown Voltage: 50 V (CNW82/83 only).
- Collector-Emitter Breakdown Voltage: 80 V (CNW84/85 only).
- UL recognized (File # E90700)



CNW82
CNW83
CNW84
CNW85



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Value	Units
EMITTER			
Forward Current - Continuous	I_F	100	mA
Forward Current - Peak (PW = 100 μ s, 120pps)	$I_F(pk)$	3	A
Reverse Voltage	V_R	5	V
Total Power Dissipation @ $T_A = 25^\circ\text{C}$	P_D	200	mW
Derate above 25 $^\circ\text{C}$		2.0	mW/ $^\circ\text{C}$
DETECTOR			
Collector Current-Continuous	I_C	100	mA
Emitter-Collector Voltage	V_{ECO}	7	V
Collector-Emitter Voltage	V_{CEO}	50	V
(CNW82/CNW83)		80	
Collector-Base Voltage	V_{CBO}	70	V
(CNW85)		120	
Total Power Dissipation @ $T_A = 25^\circ\text{C}$	P_D	200	mW
Derate above 25 $^\circ\text{C}$		2.0	mW/ $^\circ\text{C}$
TOTAL DEVICE			
Storage Temperature Range	T_{stg}	-55 to 150	$^\circ\text{C}$
Ambient Operating Temperature Range	T_A	-40 to 100	$^\circ\text{C}$
Lead Soldering Temperature (1/16" from case, 10 sec. duration)	T_L	260	$^\circ\text{C}$

CNW82, CNW83, CNW84, CNW85

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ Unless otherwise specified)							
Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit	
EMITTER							
Input Forward Voltage	($I_F = 10\text{ mA}$)	V_F	—	1.20	1.50	V	
Reverse Leakage Current	($V_R = 5.0\text{ V}$)	I_R	—	—	10	μA	
DETECTOR							
Collector-Emitter Breakdown Voltage	(CNW82/83) ($I_C = 1.0\text{ mA}$)	BV_{CEO}	50	100	—	V	
	(CNW84/85)		80	100	—		
Emitter-Collector Breakdown Voltage	($I_E = 0.1\text{ mA}$)	BV_{ECO}	7	10	—	V	
Collector-Base Breakdown Voltage	(CNW83) ($I_C = 0.1\text{ mA}$)	BV_{CBO}	70	100	—	V	
	(CNW85)		120	140	—		
Collector-Emitter Dark Current	($T_A = 25^\circ\text{C}$) ($T_A = 70^\circ\text{C}$)	($V_{CE} = 10\text{ V}, I_F = 0$)	I_{CEO}	—	1	50	nA
				—	0.1	10	μA
Collector-Base Cut-off Current	(CNW83/85)	($V_{CB} = 10\text{ V}, I_F = 0$)	I_{CBO}	—	—	20	nA
COUPLED							
Collector-Emitter Saturation Voltage	($I_C = 4\text{ mA}, I_F = 10\text{ mA}$)	$V_{CE(sat)}$	—	0.15	0.4	V	
Isolation Voltage	(DC Value) (RMS Value)	($t = 1.0\text{ min.}$) ⁽¹⁾ ($t = 1.0\text{ min.}$) ⁽¹⁾	V_{ISO}	8.34	—	—	kV
				5.9	—	—	
Isolation Resistance	($V_{I-O} = 500\text{ V}$)	R_{ISO}	1	10	—	$\text{T}\Omega$	
Isolation Capacitance	($V_{I-O} = 0, f = 1.0\text{ MHz}$)	C_{ISO}	—	0.4	1	pF	
Current Transfer Ratio	(CNW82/83) (CNW84/85)	($I_F = 10\text{ mA}, V_{CE} = 0.4\text{ V}$) ($I_F = 10\text{ mA}, V_{CE} = 5\text{ V}$)	CTR	0.4	0.8	—	%
				0.63	1.5	3.2	
Capacitance	(CNW83/85)	($V_{CB} = 10\text{ V}, f = 1\text{ MHz}$)	C_{CB}	—	4.5	—	pF
Turn-on Time	($I_C = 2\text{ mA}, V_{CC} = 5\text{ V}, R_L = 100\ \Omega$) ($I_C = 2\text{ mA}, V_{CC} = 5\text{ V}, R_L = 1\text{ k}\Omega$)	T_{ON}	—	3	—	μs	
				—	12	—	
Turn-off Time	($I_C = 2\text{ mA}, V_{CC} = 5\text{ V}, R_L = 100\ \Omega$) ($I_C = 2\text{ mA}, V_{CC} = 5\text{ V}, R_L = 1\text{ k}\Omega$)	T_{OFF}	—	3	—	μs	
				—	12	—	

NOTE:

1. Every product is tested with pins 1, 2 and 3 shorted together, and pins 4, 5 and 6 shorted together.

CNW82, CNW83, CNW84, CNW85

Fig. 1 Forward Current vs. Forward Voltage

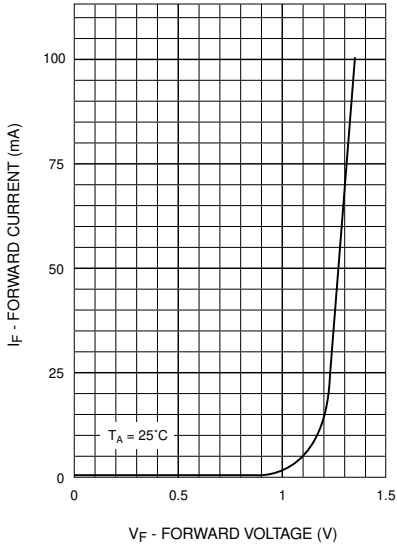


Fig. 2 Collector Current vs. Forward Current (for CNW84 and CNW85)

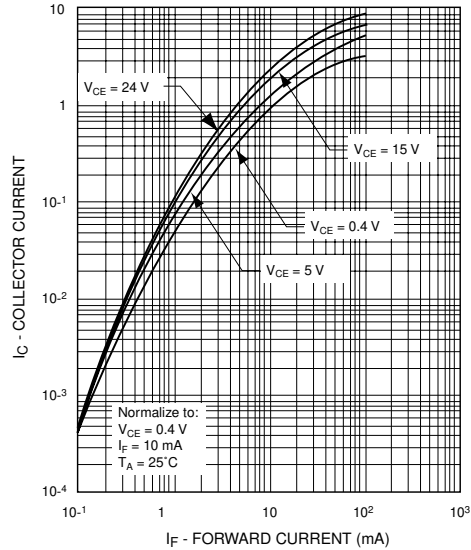


Fig. 3 Collector Current vs. Forward Current (for CNW82 and CNW83)

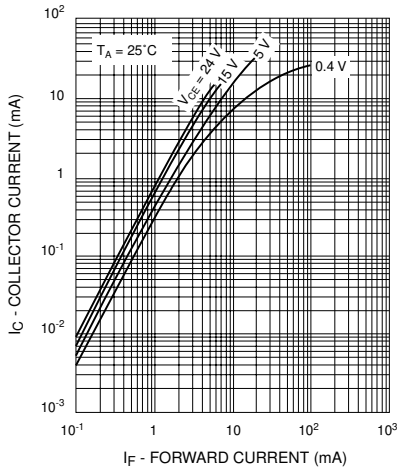


Fig. 4 Collector Current vs. Collector-Emitter Voltage

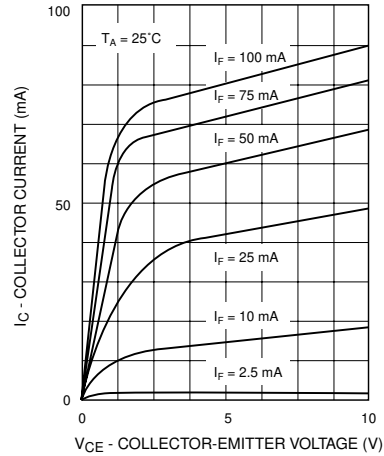


Fig. 5 Collector Current vs. Ambient Temperature (for CNW82 and CNW83)

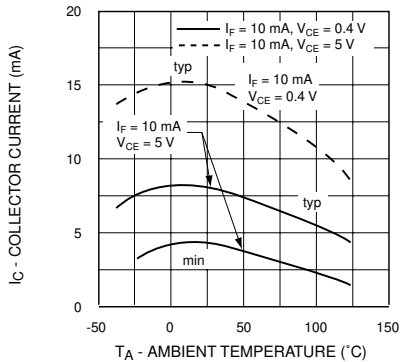
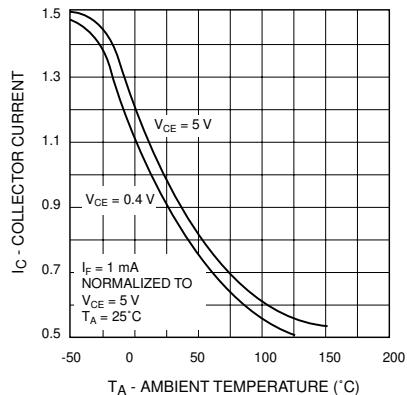
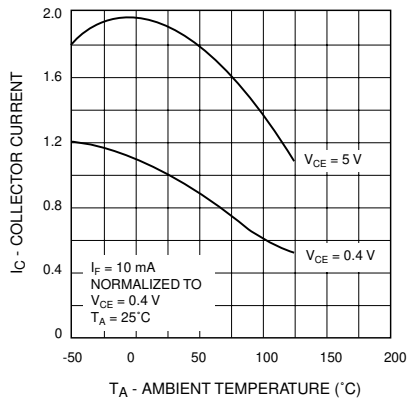


Fig. 6 Collector Current vs. Ambient Temperature (for CNW84 and CNW85)

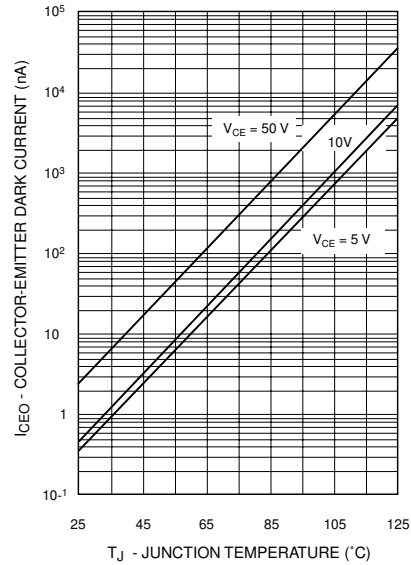


CNW82, CNW83, CNW84, CNW85

**Fig. 7 Collector Current vs. Ambient Temperature
(for CNW84 and CNW85)**



**Fig. 8 Collector-Emitter Dark Current
vs. Junction Temperature**



**Fig. 9 Collector-Emitter Saturation Voltage
vs. Collector Current**

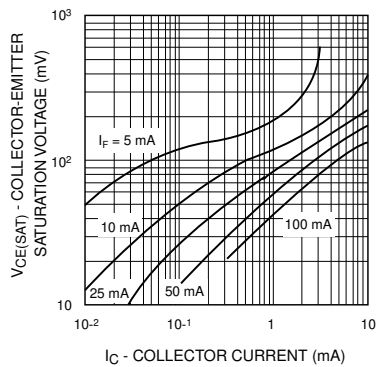
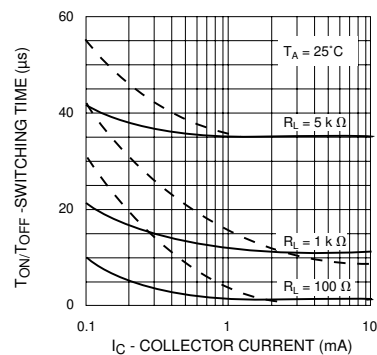
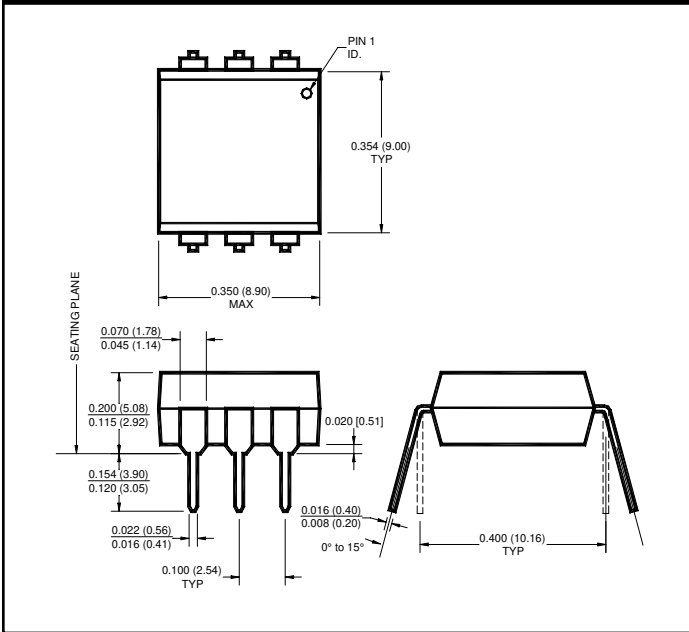


Fig. 10 Rise and Fall Time vs. Collector Current

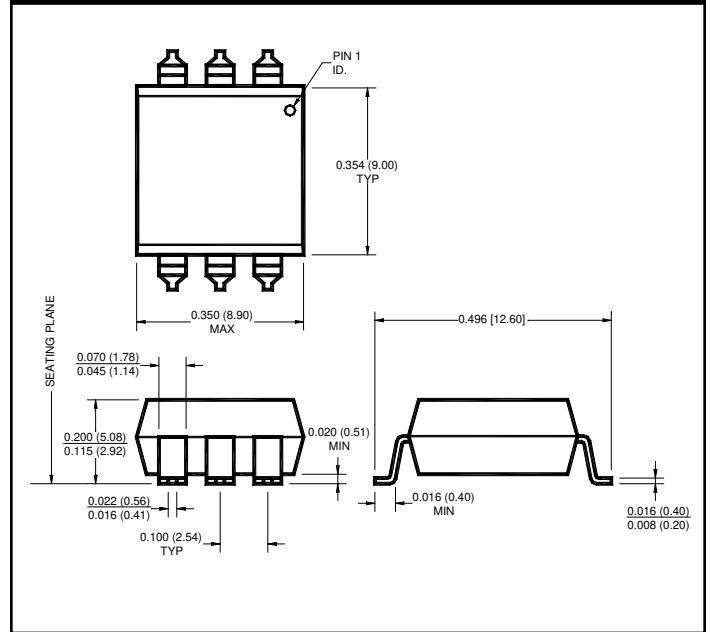


CNW82, CNW83, CNW84, CNW85

Package Dimensions (Through Hole)



Package Dimensions (Surface Mount)



NOTE

All dimensions are in inches (millimeters)

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